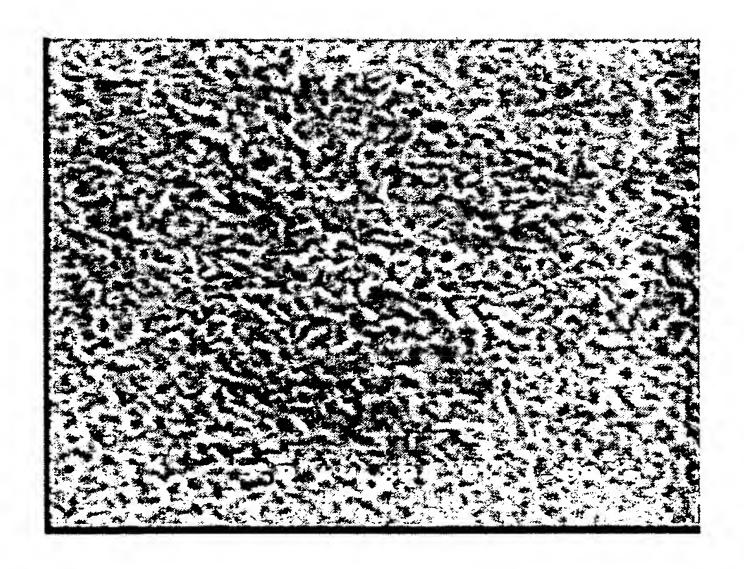
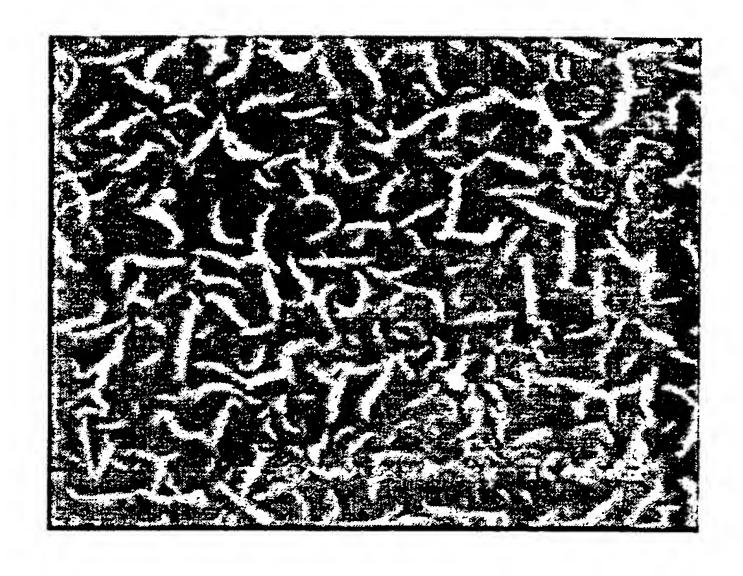


 $1 \mu m$

FIG. 8

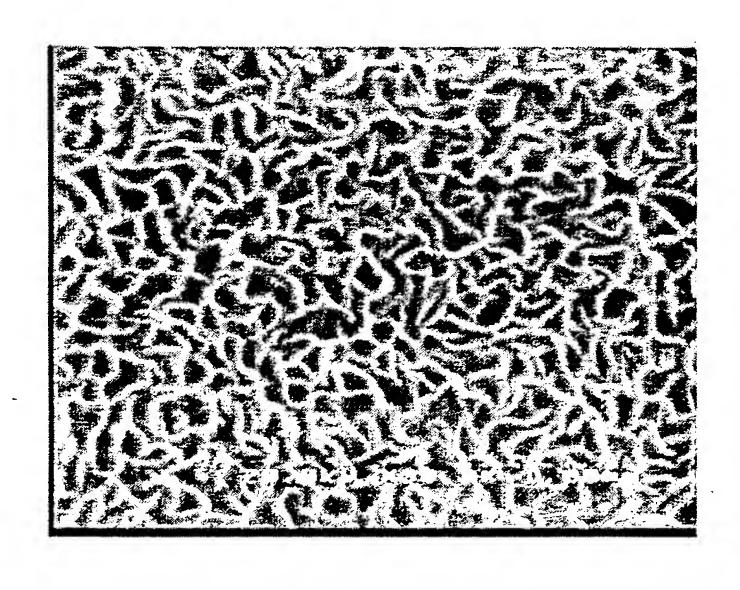


 $1 \mu m$

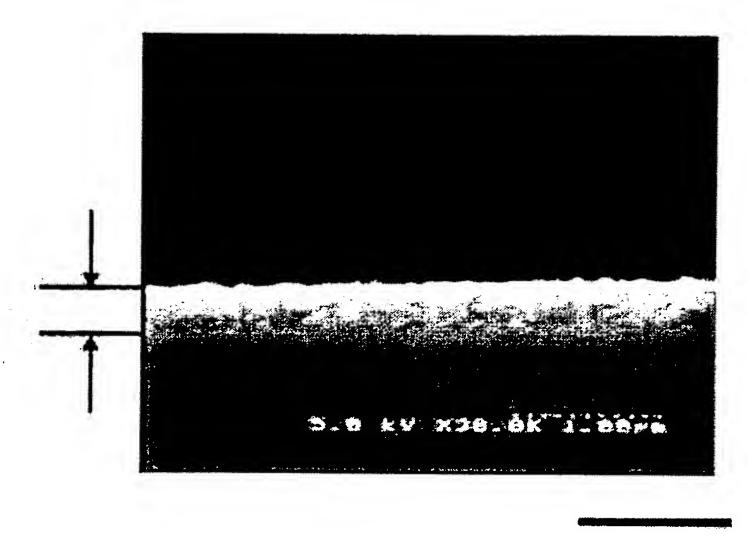


 $1 \mu m$

FIG. 10

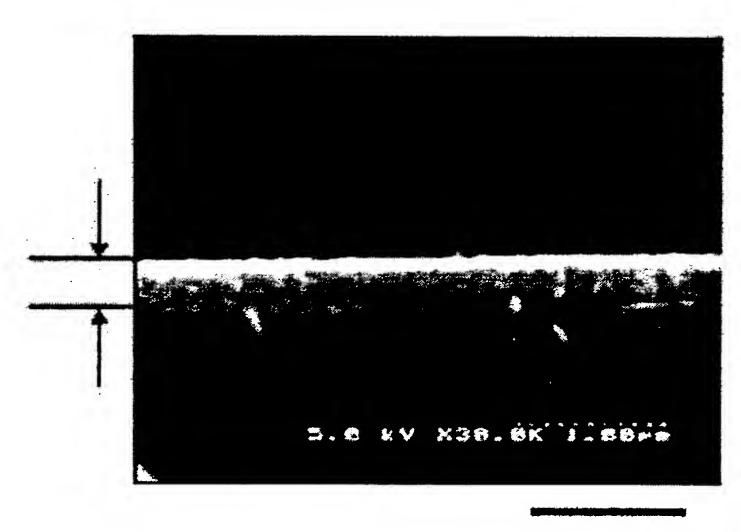


 $1 \mu m$

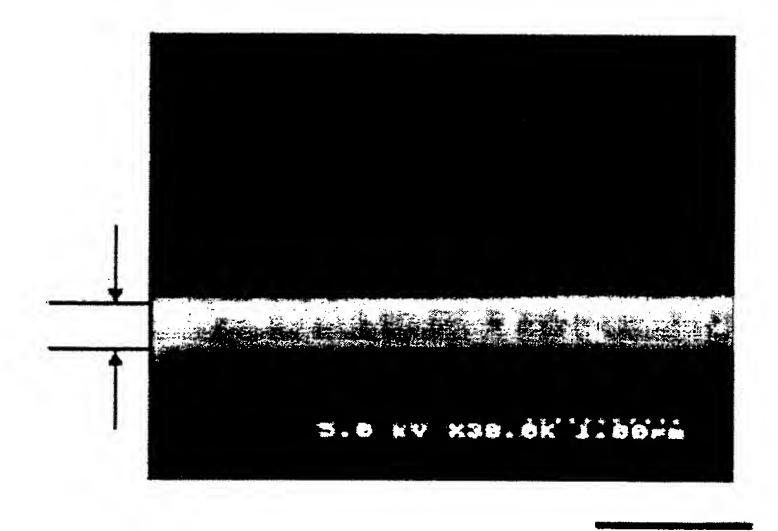


 $1 \mu m$

FIG. 12

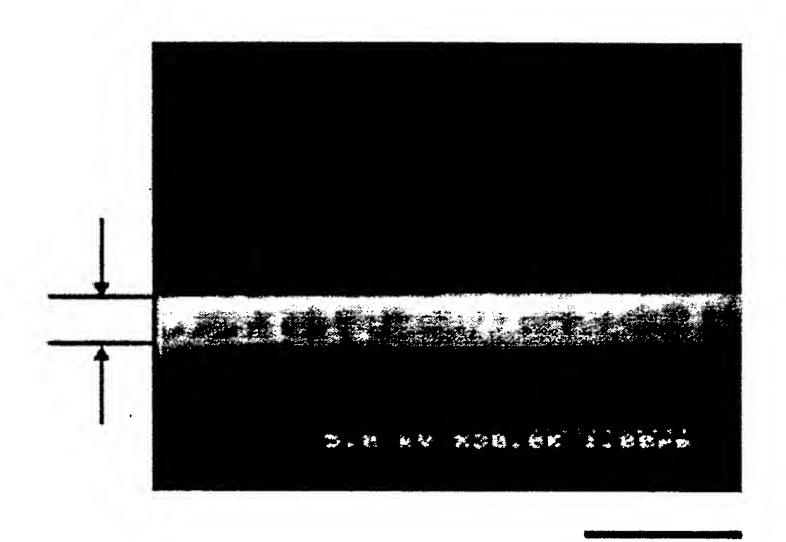


 $1~\mu\,\mathrm{m}$



 $1 \mu m$

FIG. 14



 $1 \mu m$

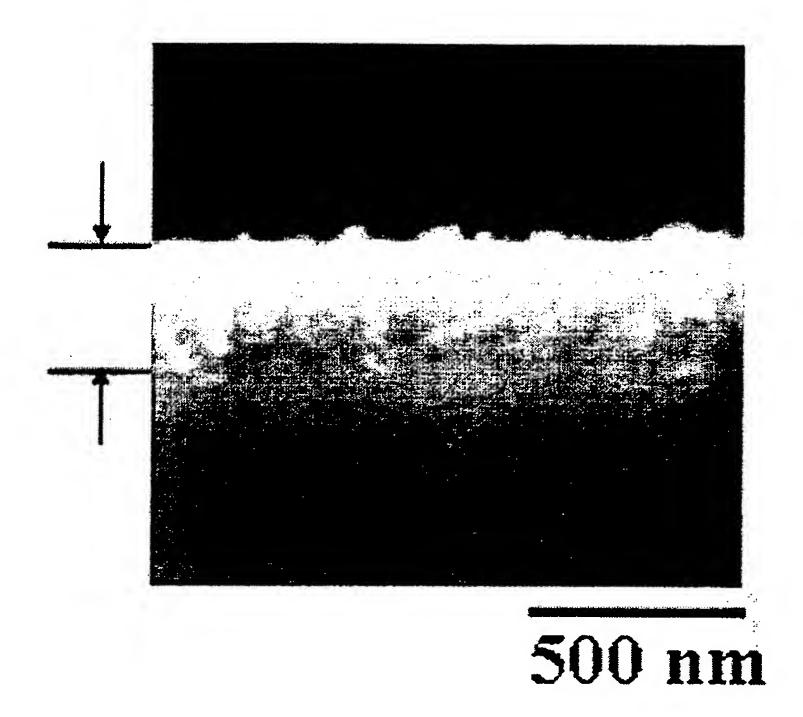
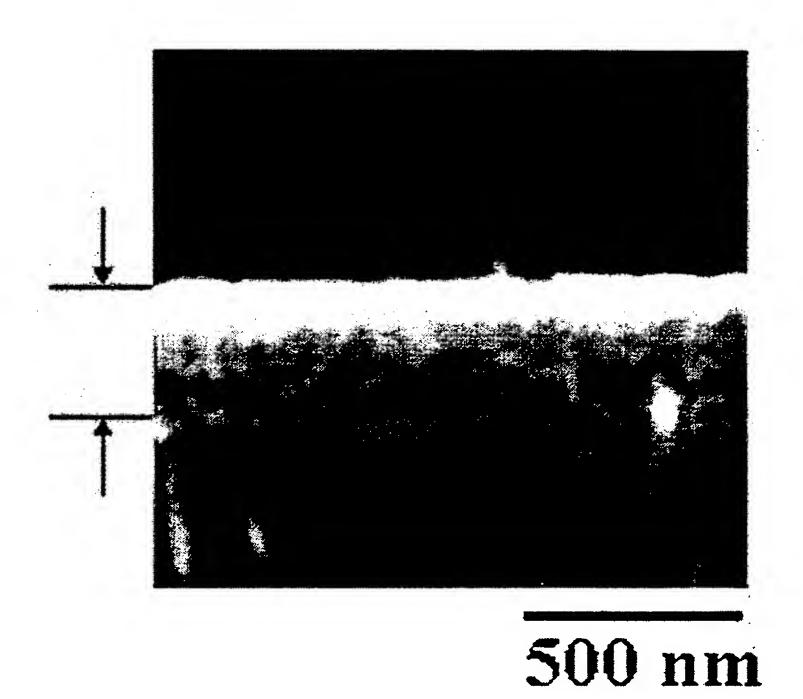


FIG. 16



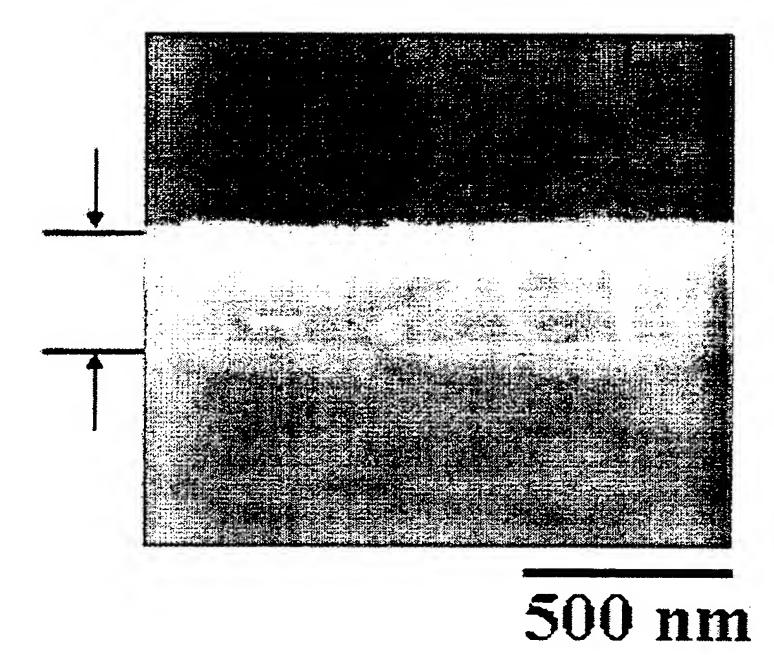
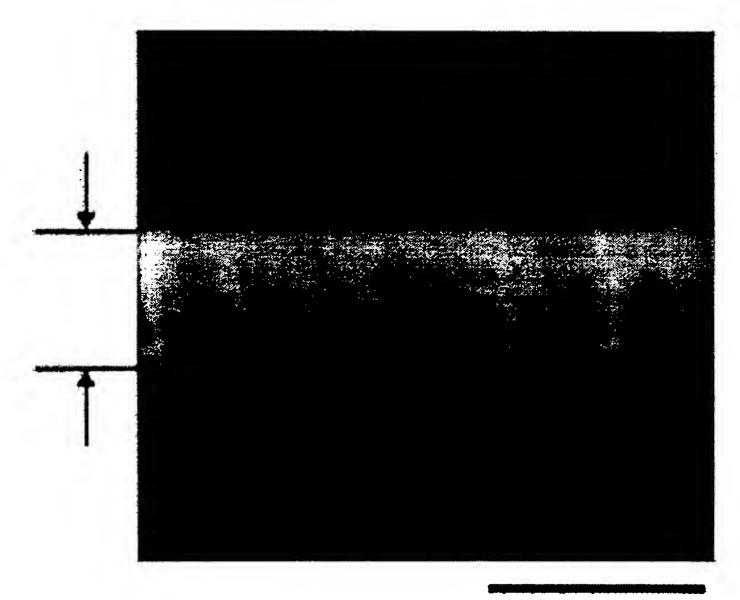
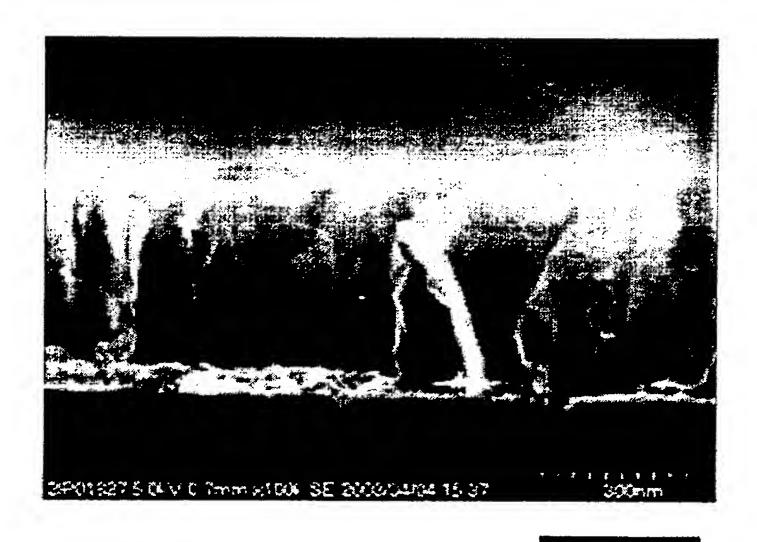


FIG. 18

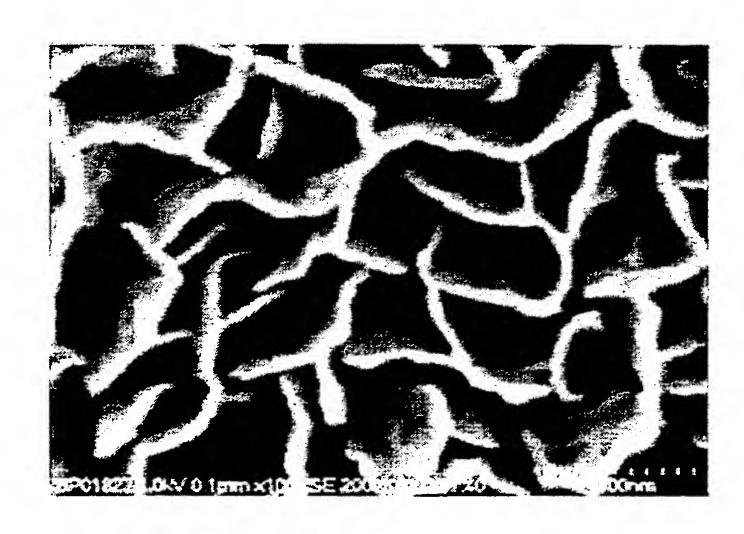


500 nm

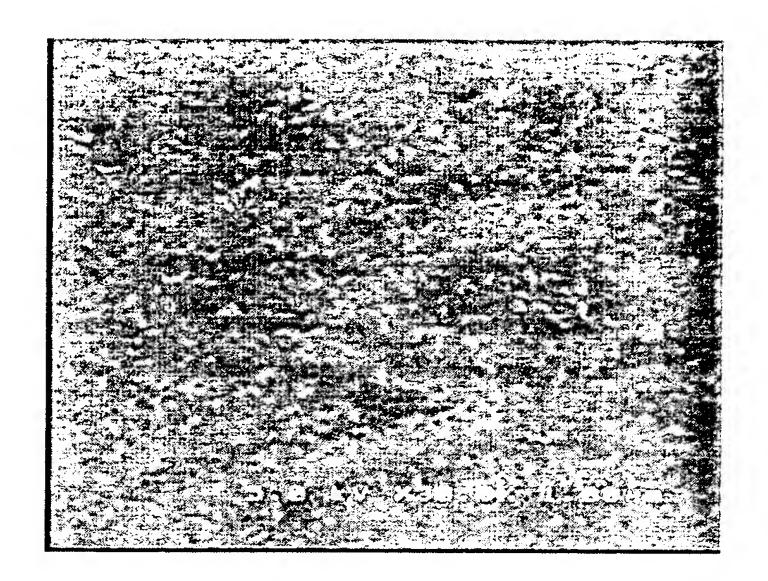


300 nm

FIG. 20

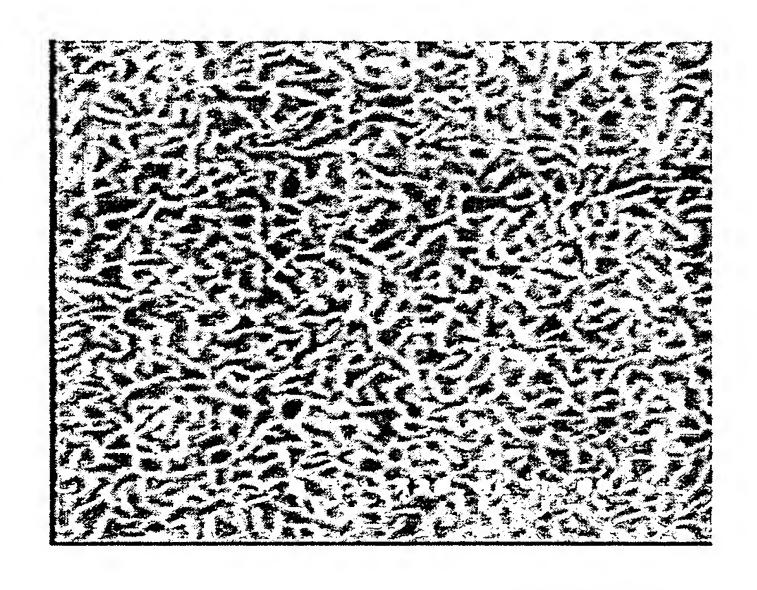


300 nm

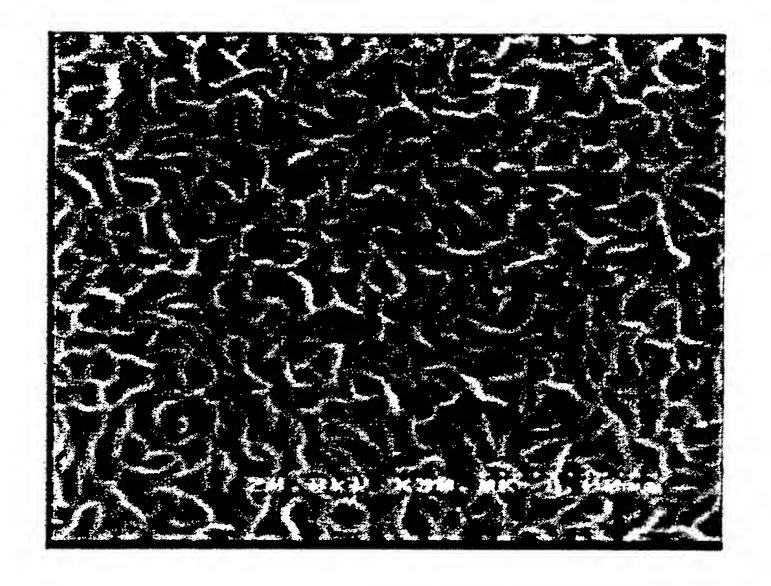


 $1 \mu m$

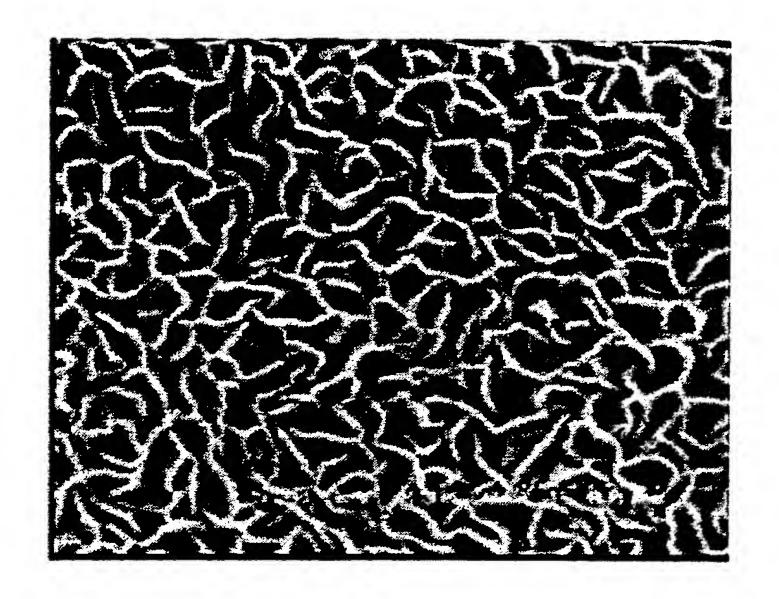
FIG. 22



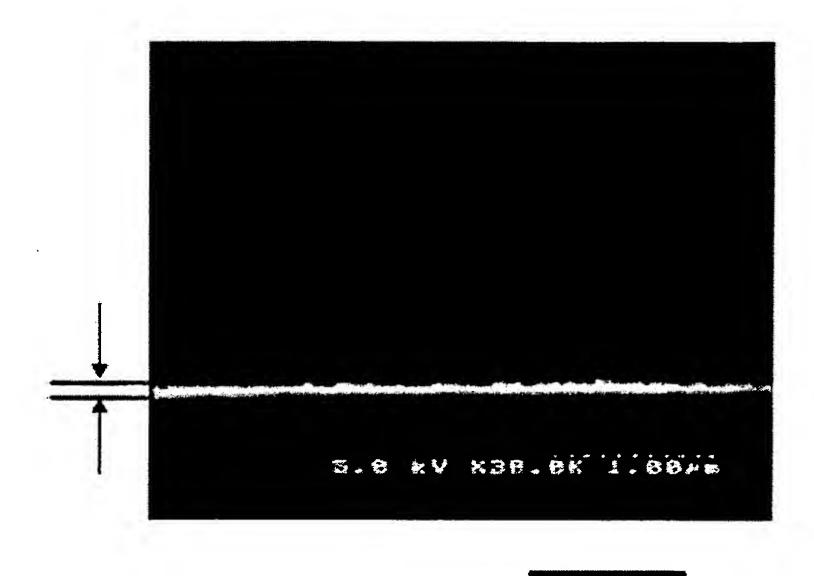
 $1 \mu m$



 $1 \mu m$

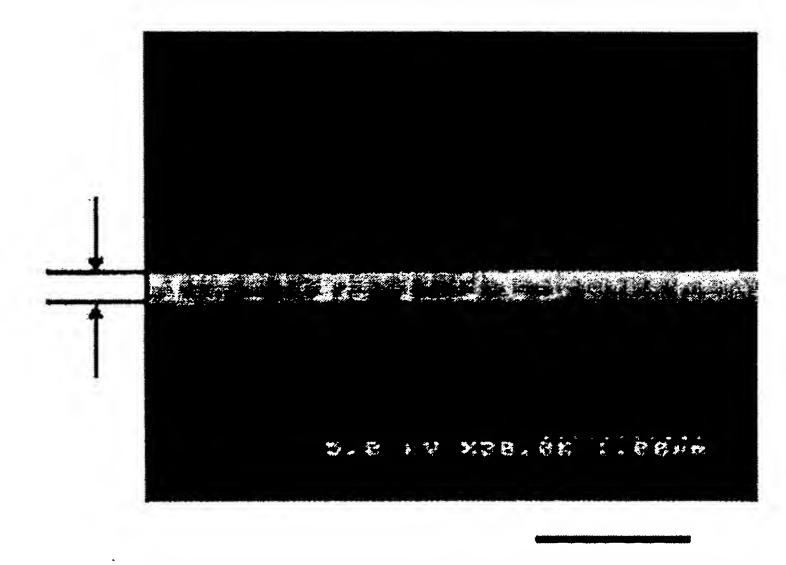


 $1 \mu m$

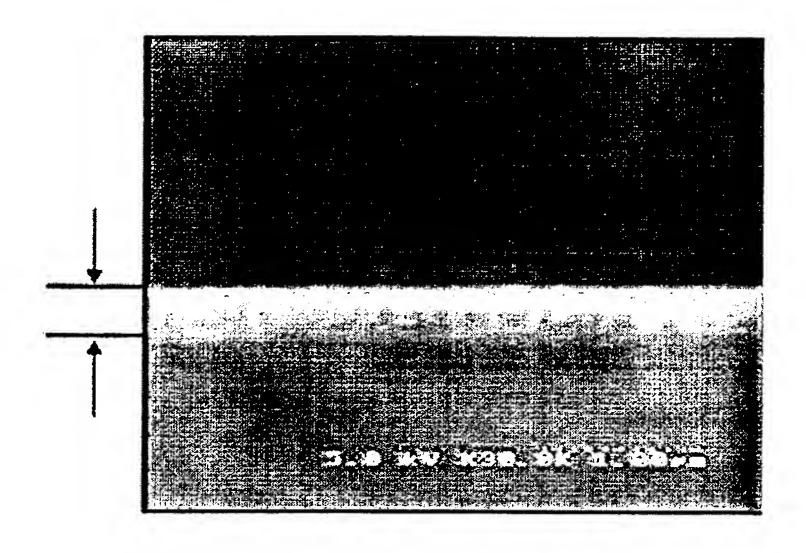


 $1 \mu m$

FIG. 26

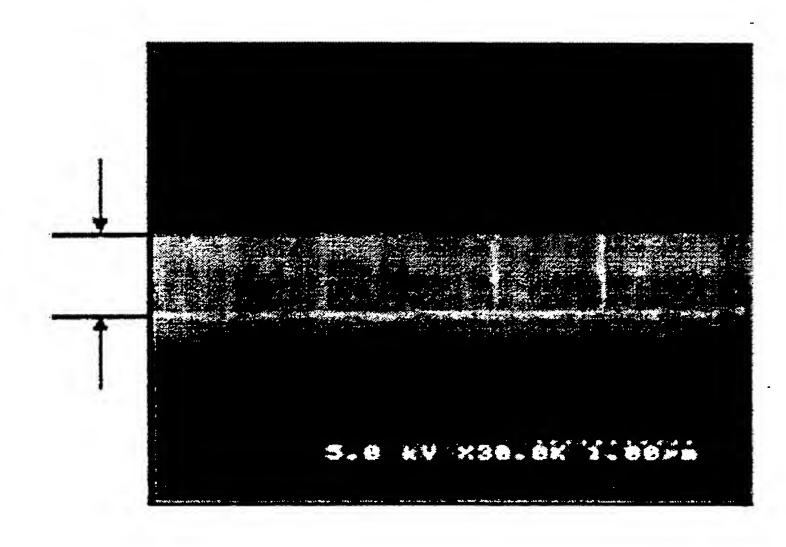


 $1 \mu m$



 $1 \mu m$

FIG. 28



 $1 \mu m$

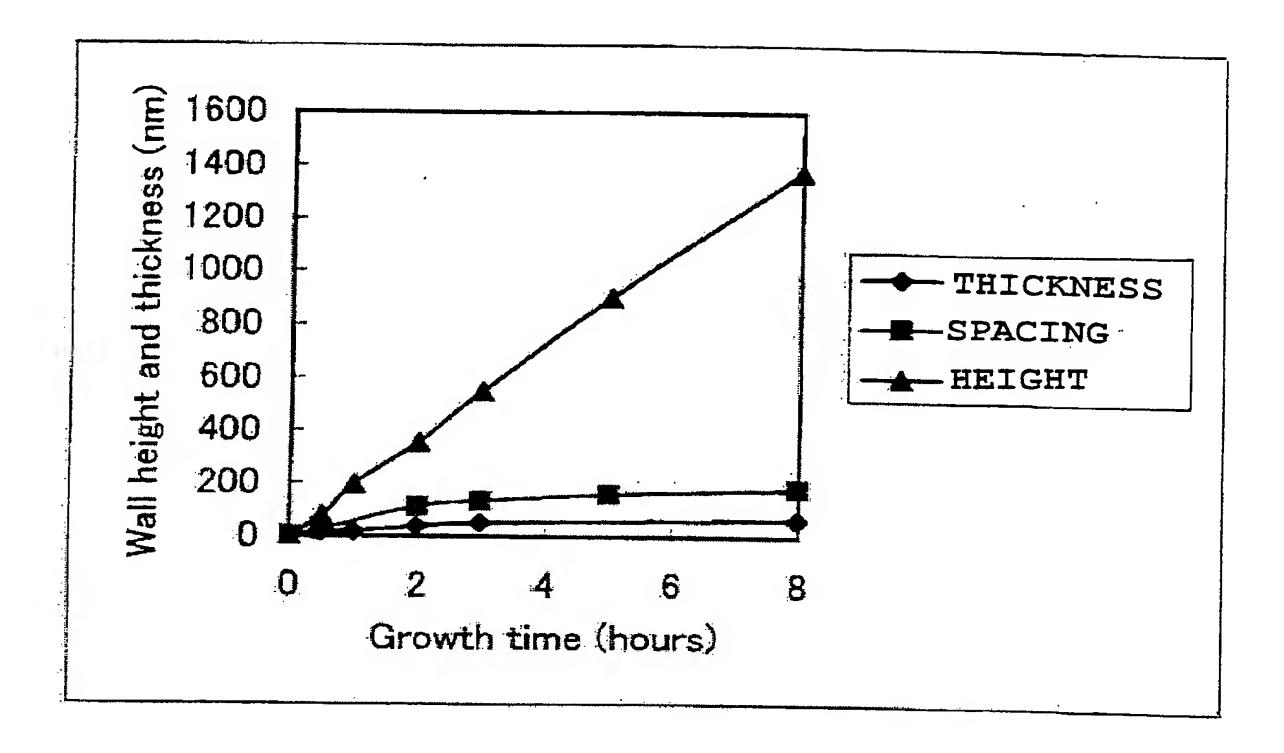
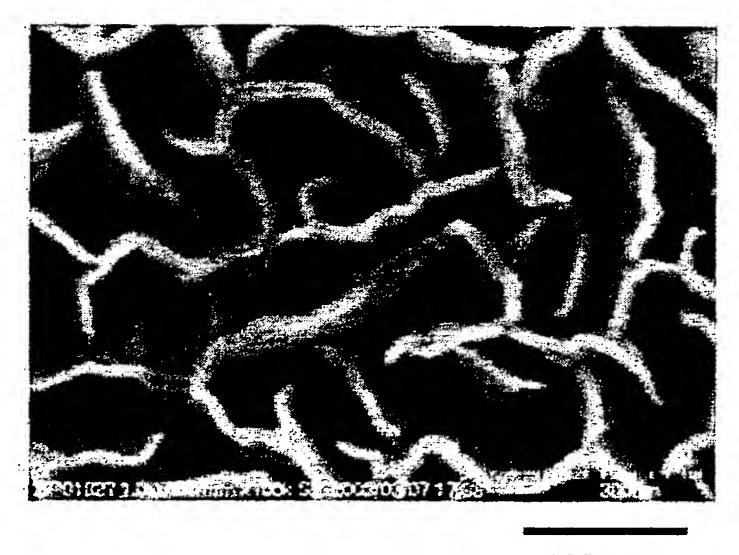


FIG. 30



300 nm

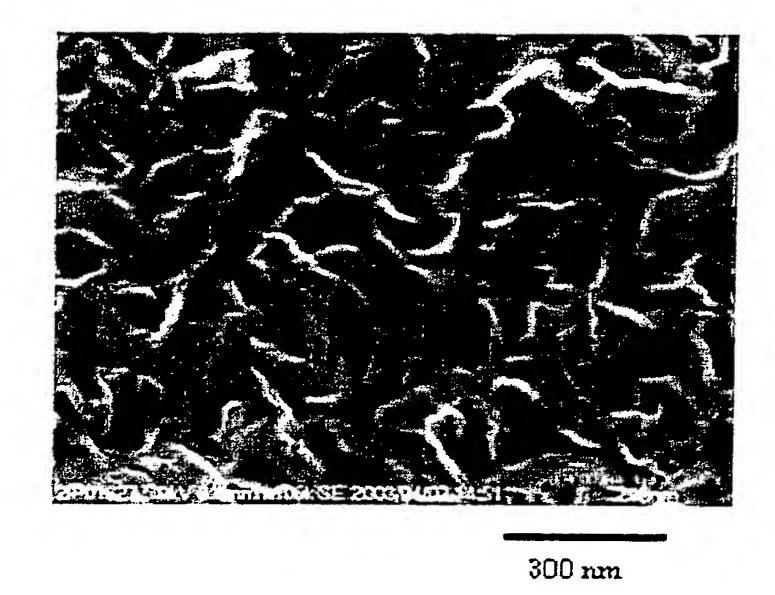
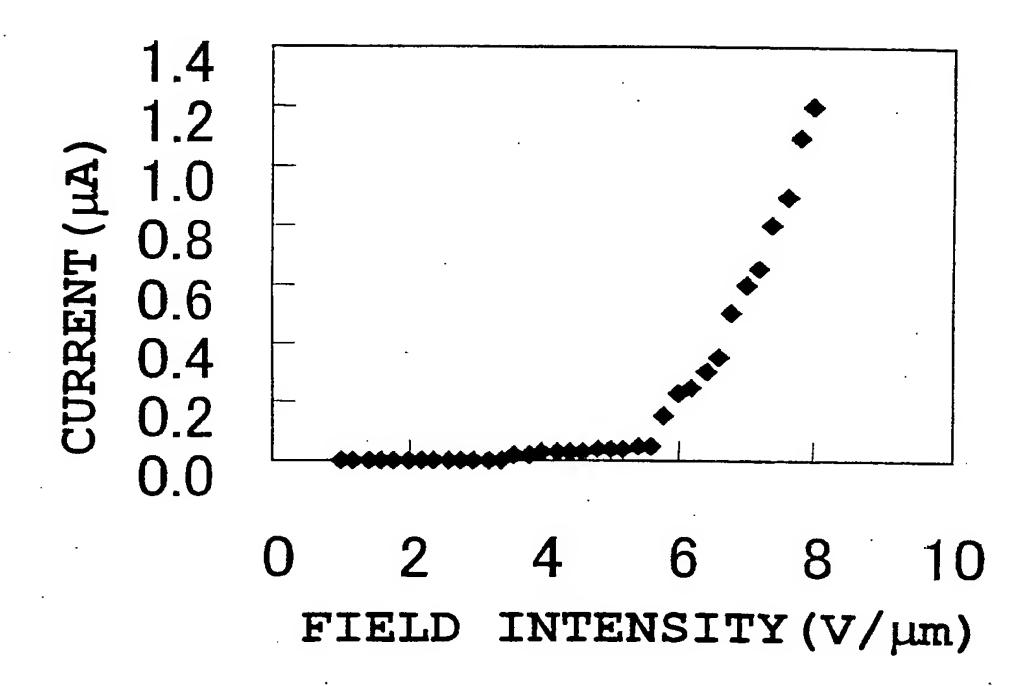
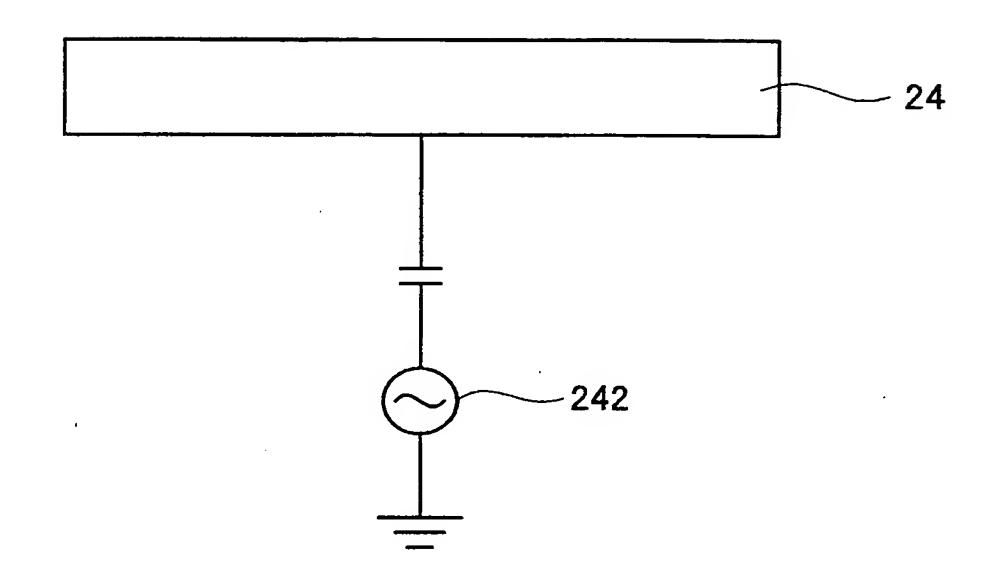
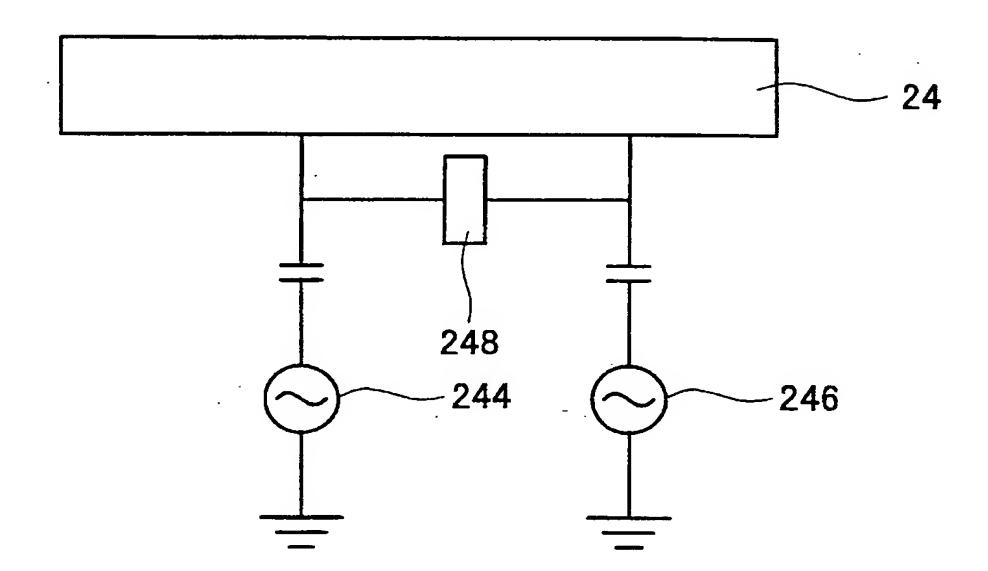


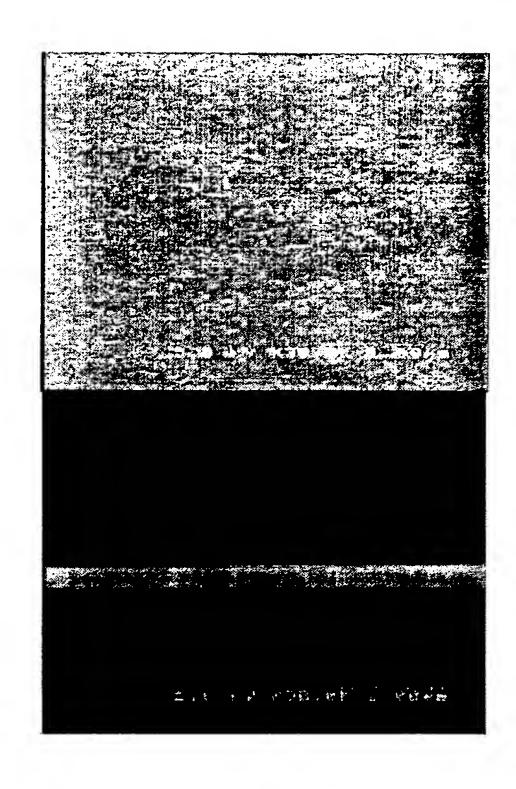
FIG. 32

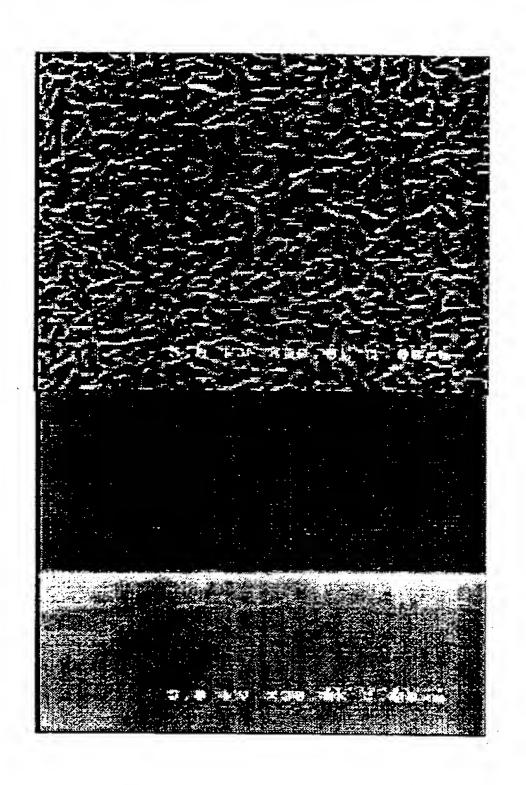






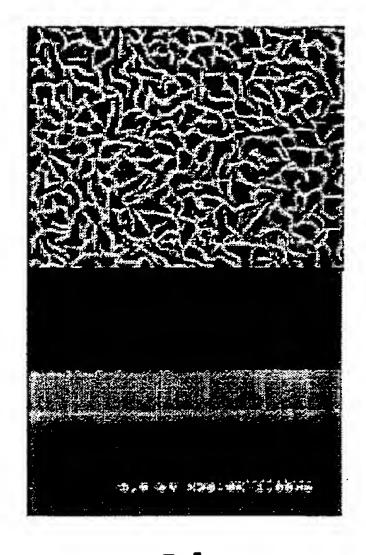
$C_2F_6/H_2(1)$

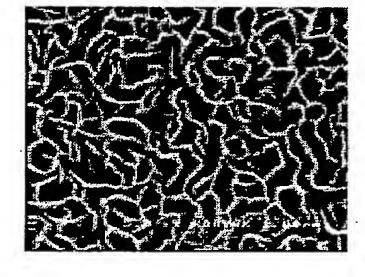


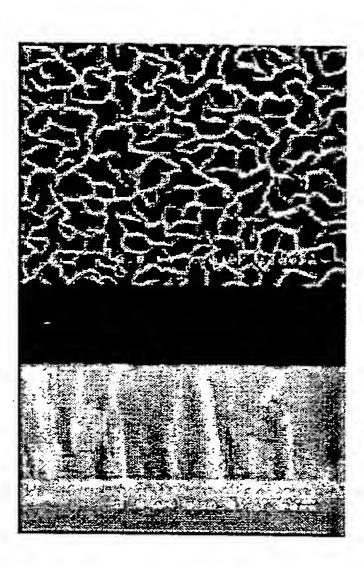


1 h 2 h

$C_2F_6/H_2(1)$



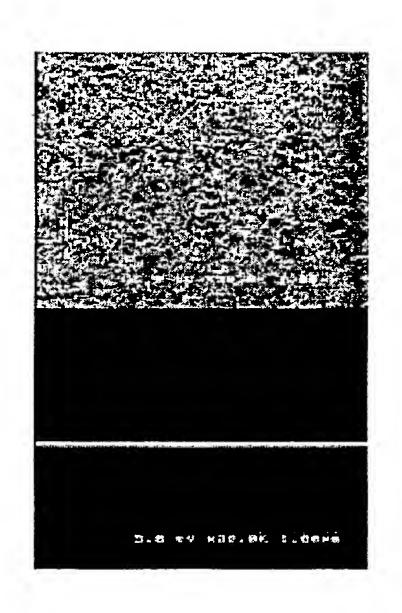


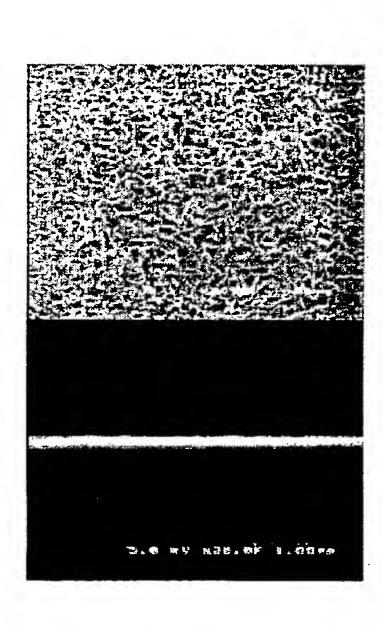


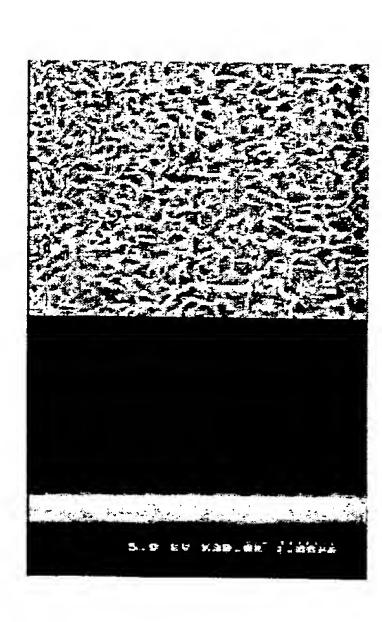
3 h

5 h

$CH_4/H_2(1)$



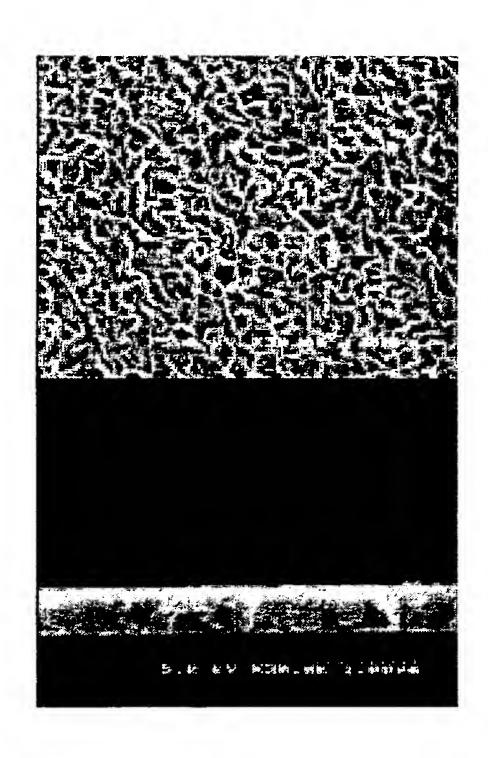




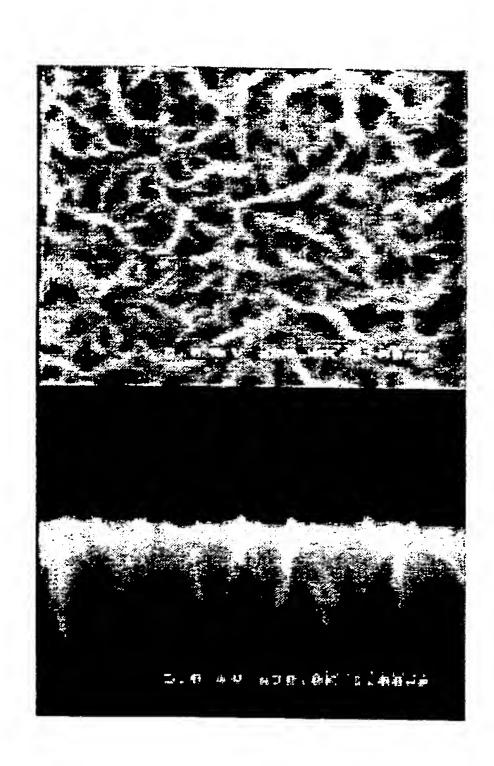
0.5 h

1 h

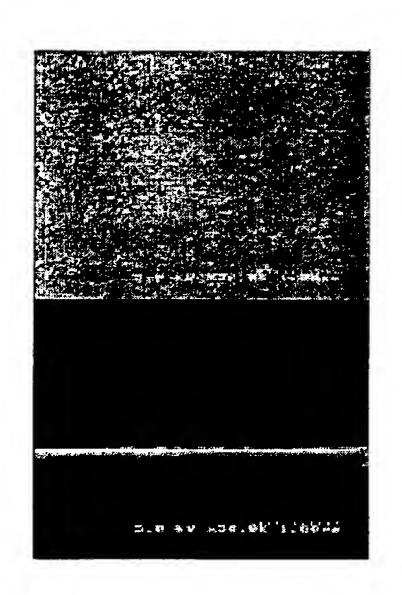
$CH_4/H_2(2)$

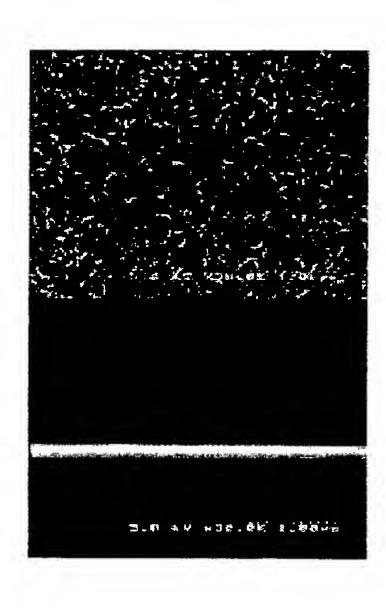


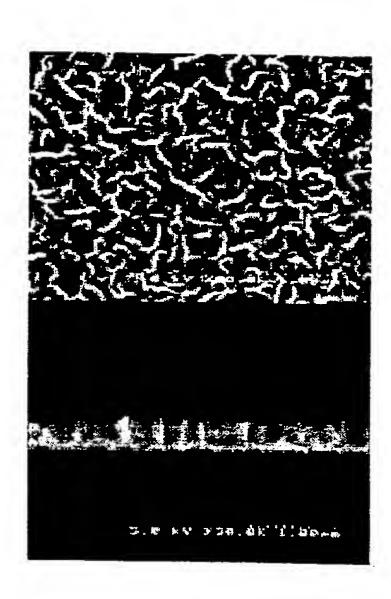
3 h



$CF_4/H_2(1)$



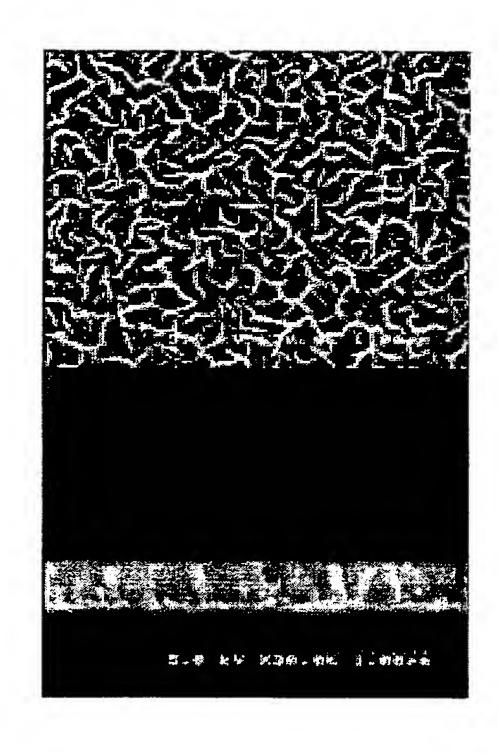


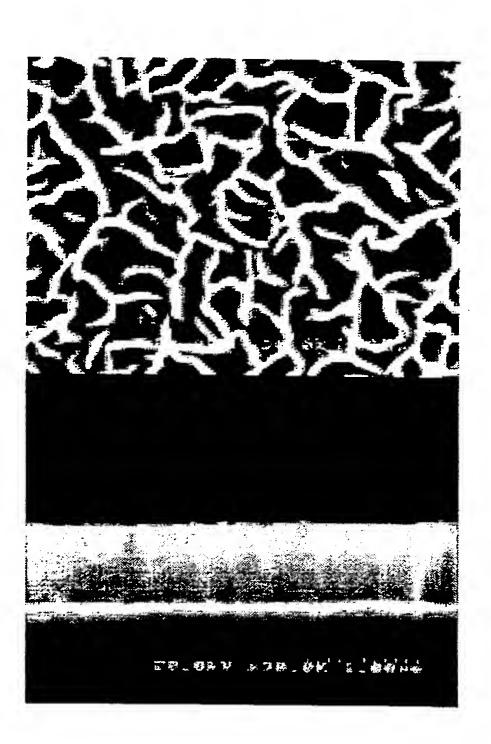


0.5 h

l h

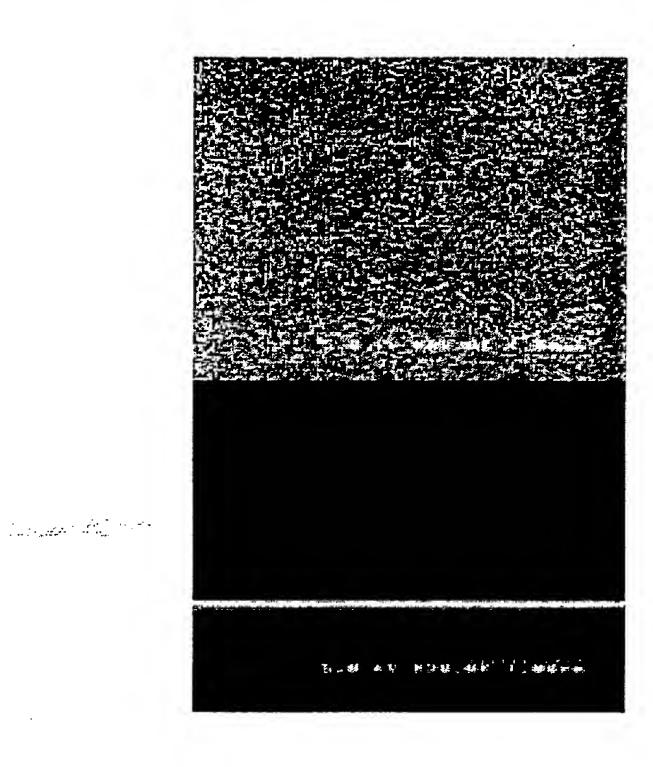
$CF_4/H_2(2)$

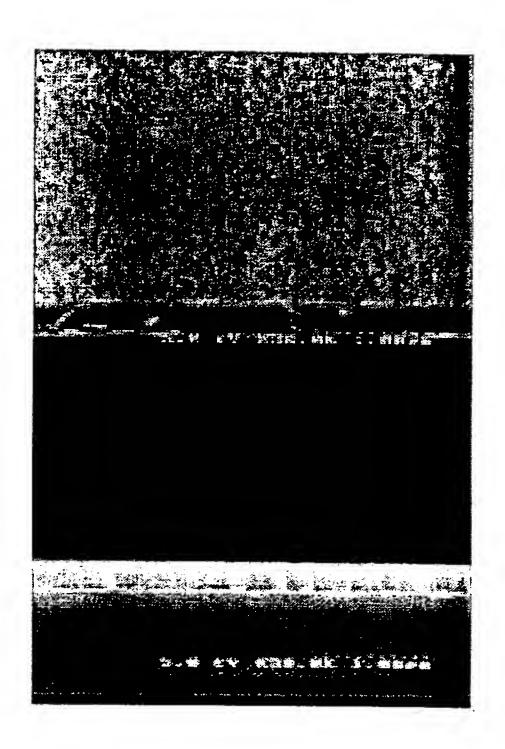




3 h 8 h

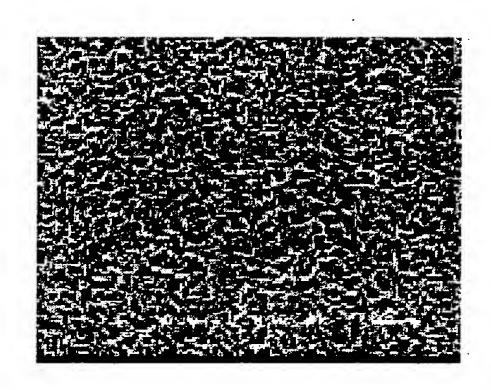
$CHF_3/H_2(1)$

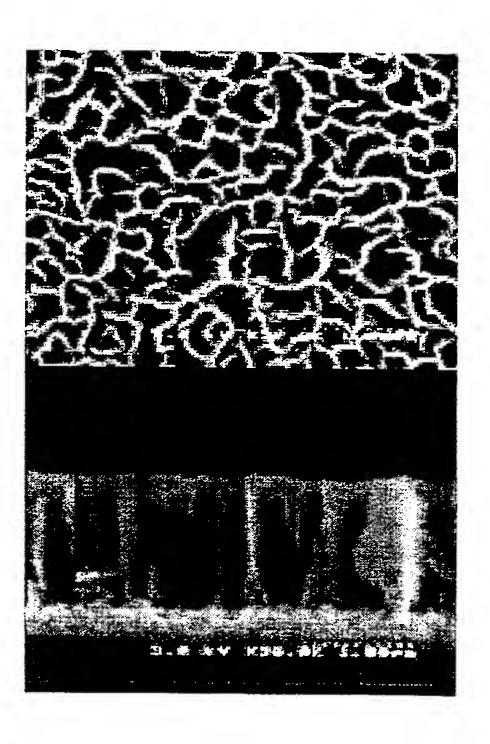




l h

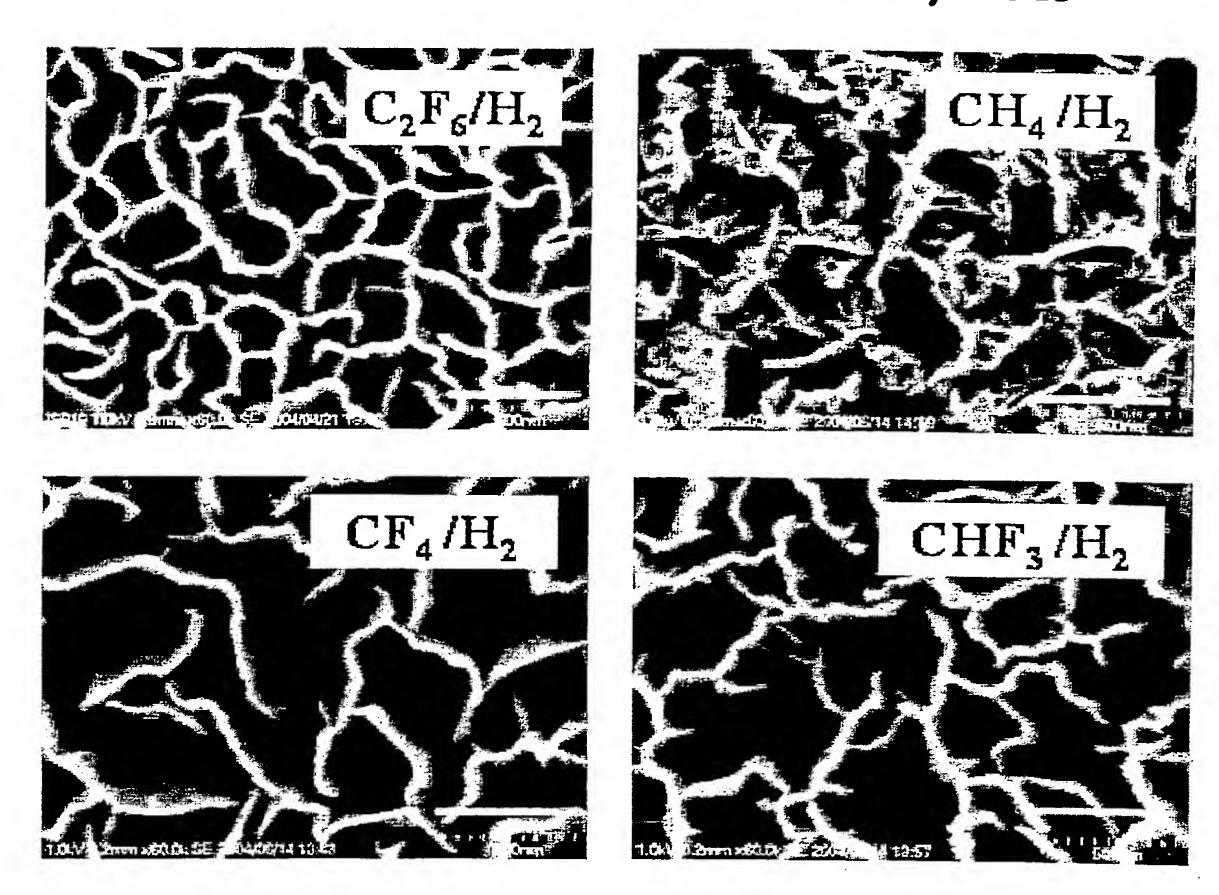
$CHF_{3}/H_{2}(2)$



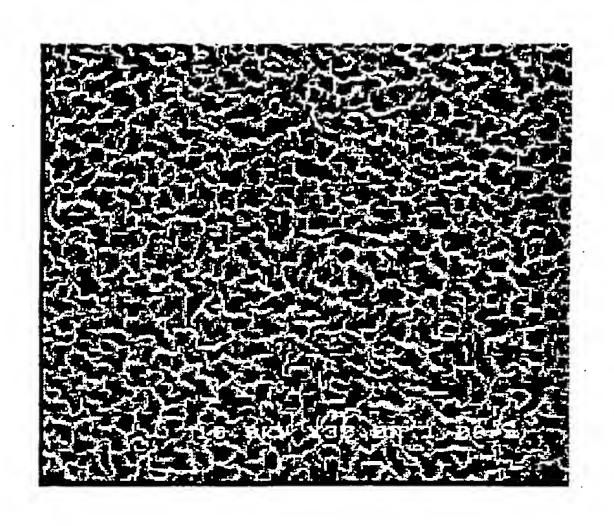


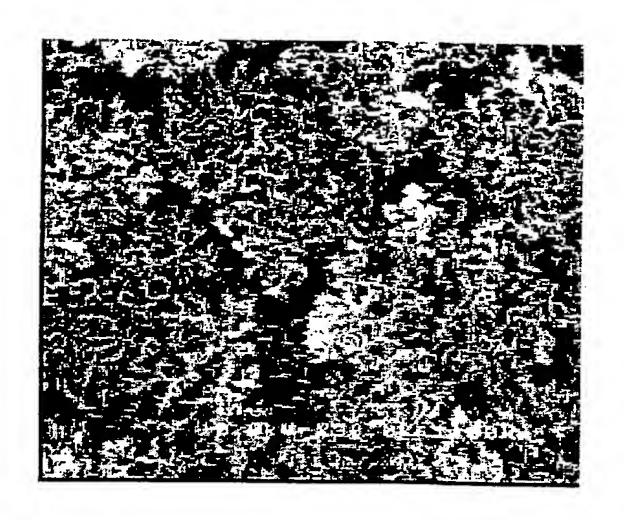
3 h 8 h

DIFFERENCE IN GAS (HIGH RESOLUTION SEM) -8h



DIFFERENCE IN SUBSTRATE (1)

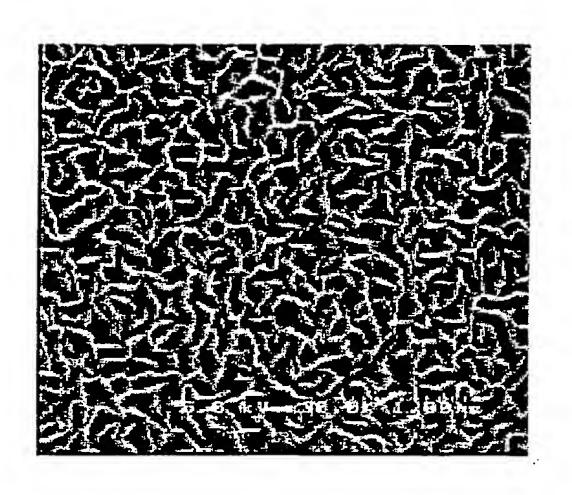


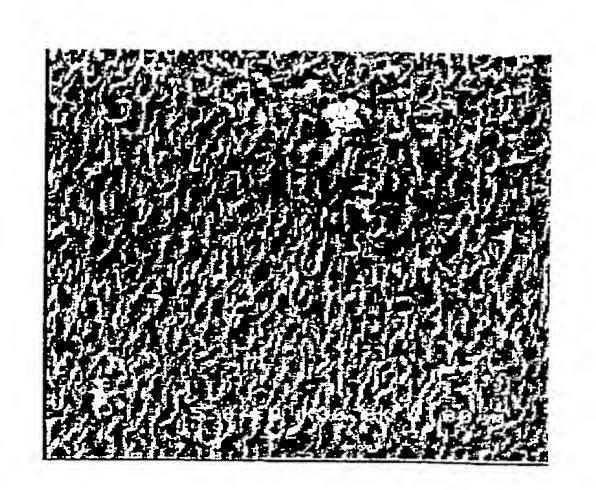


stainless steel

graphite

DIFFERENCE IN SUBSTRATE (2)





SiO₂

Ni

DIFFERENCE IN CCP (C₂F₆)

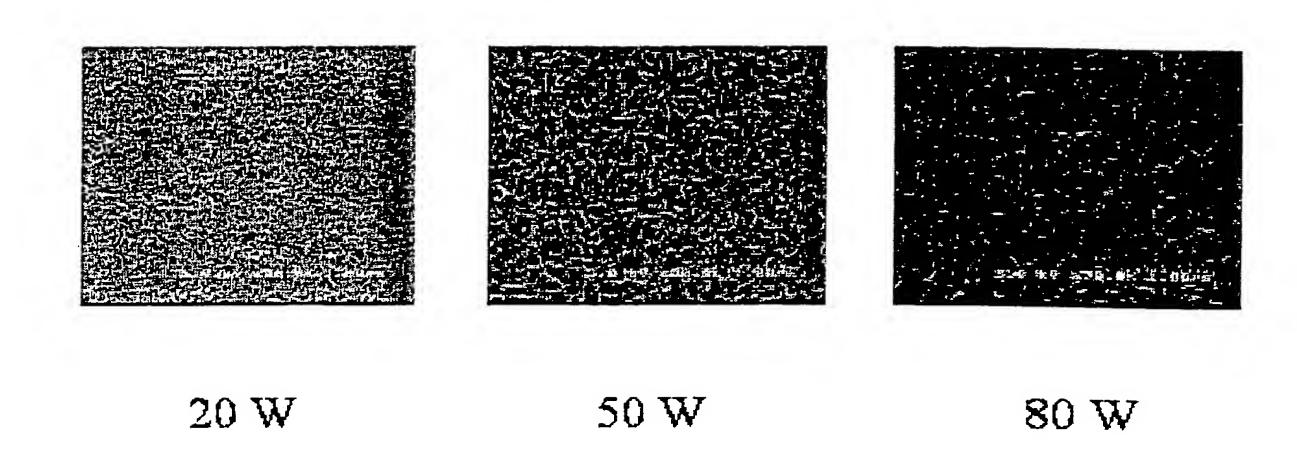
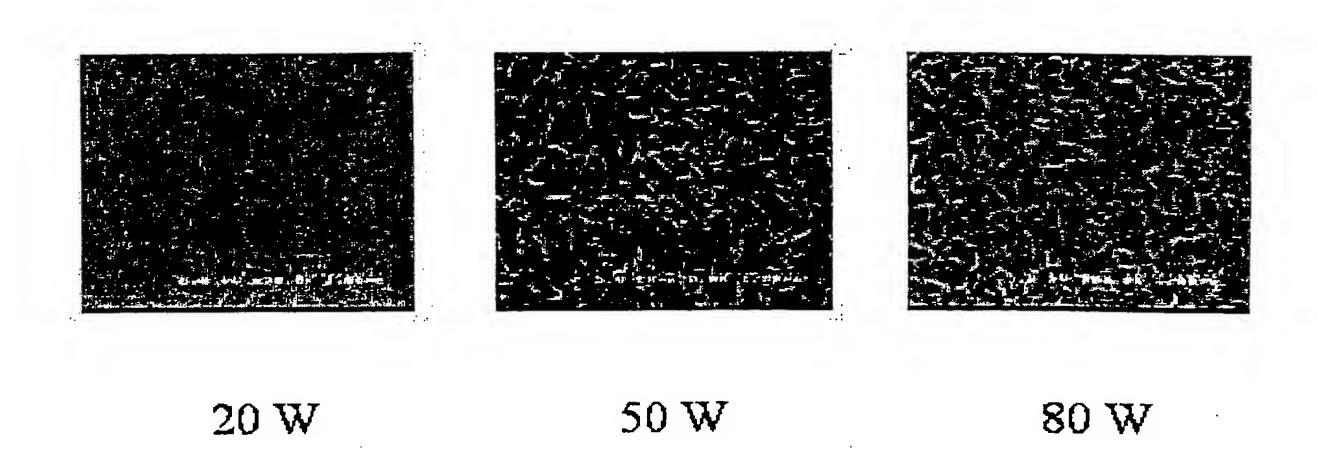


FIG. 47

DIFFERENCE IN CCP (CH₄)



DIFFERENCE IN ICP (C2F6)

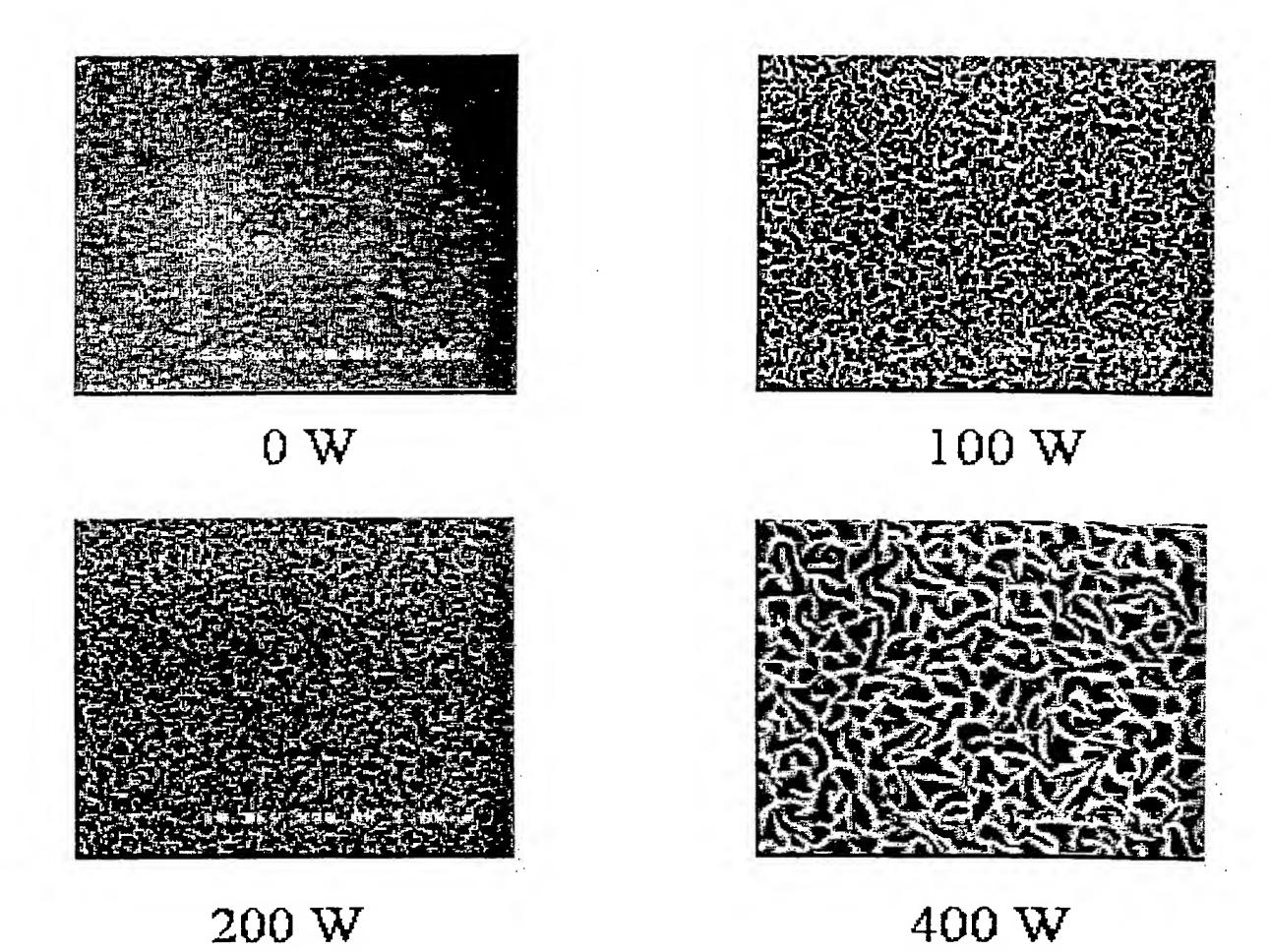
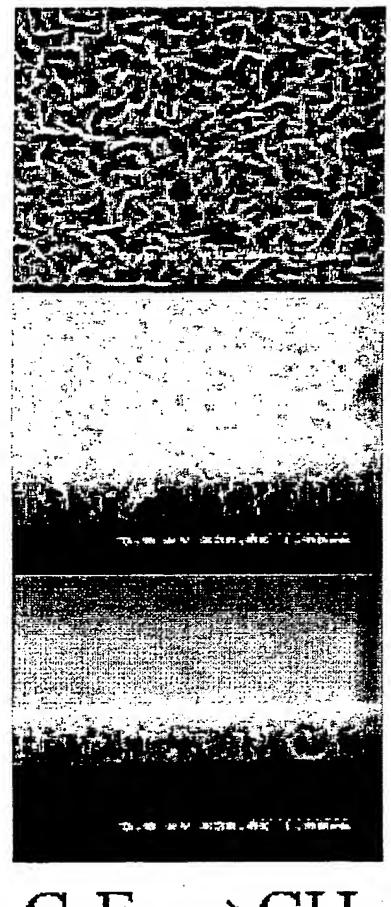
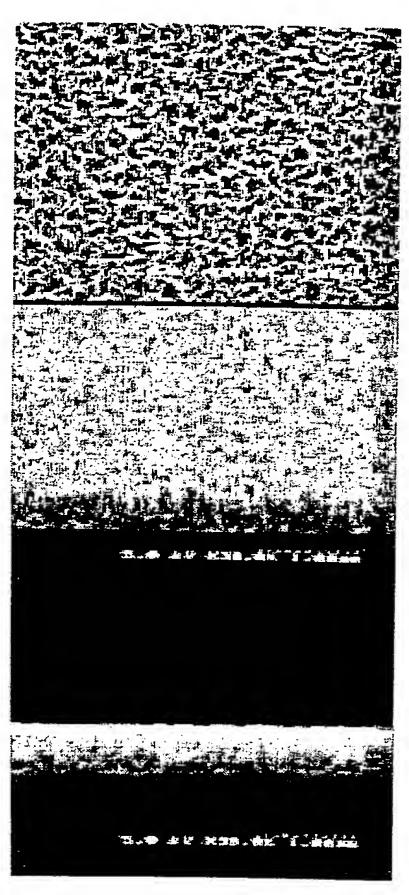


FIG. 49

USE OF TWO DIFFERENT GASES (EACH USED FOR HALF OF A GROWTH TIME OF THREE HOURS)

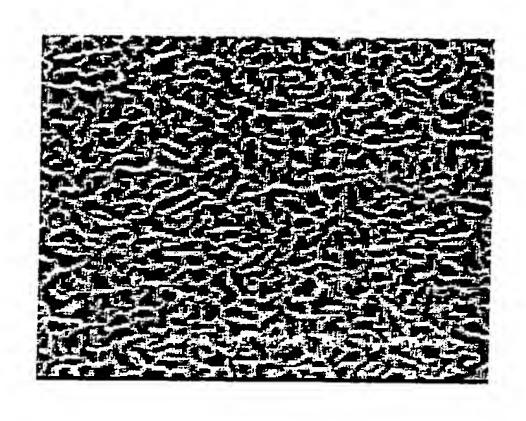


 $C_2F_6 \rightarrow CH_4$

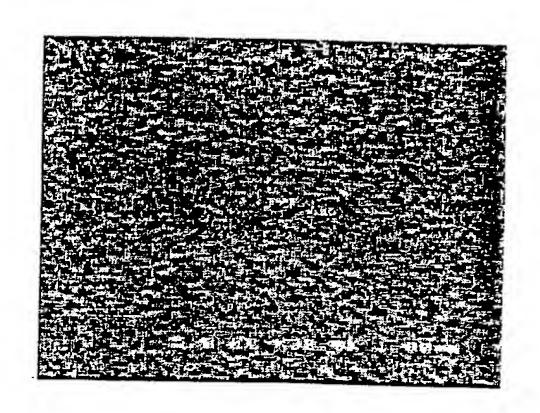


 $CH_4 \rightarrow C_2F_6$

DIFFERENCE IN FLOW RATE



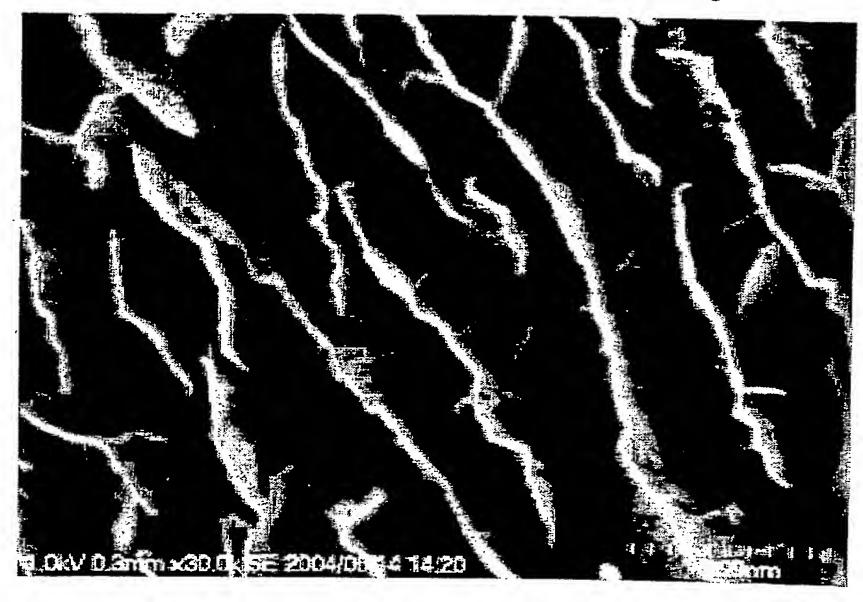
 $C_2F_6/H_2 = 7.5/30 \text{ secm}$



 $C_2F_6/H_2 = 24/24 \text{ sccm}$

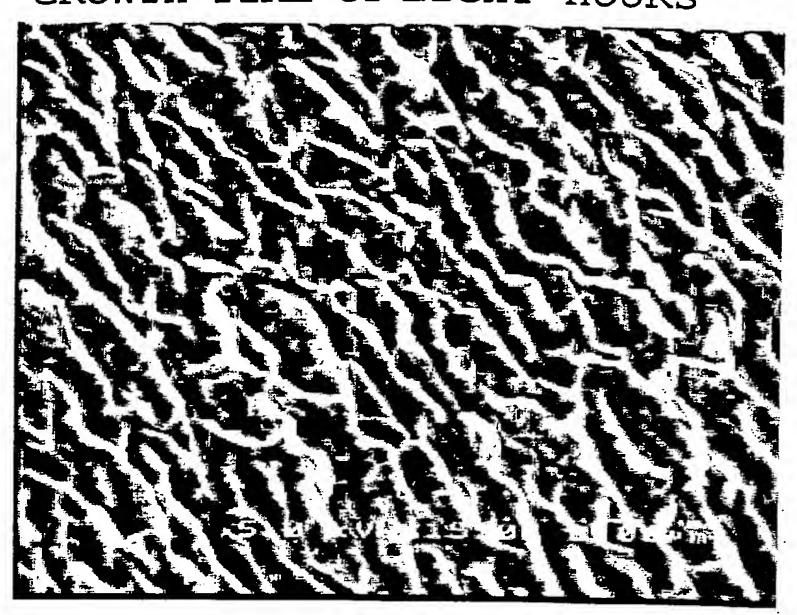
ORIENTATION

C₂F₆/H₂=20/80 CCP 100W, ICP 400W Si (100) SUBSTRATE SUBSTRATE TEMPERATURE OF 600°C GROWTH TIME OF EIGHT HOURS



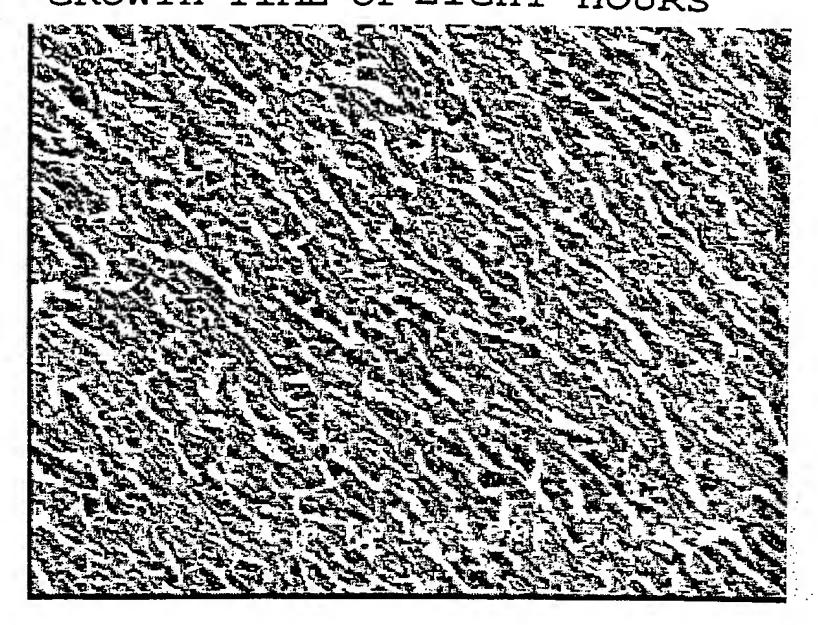
ORIENTATION

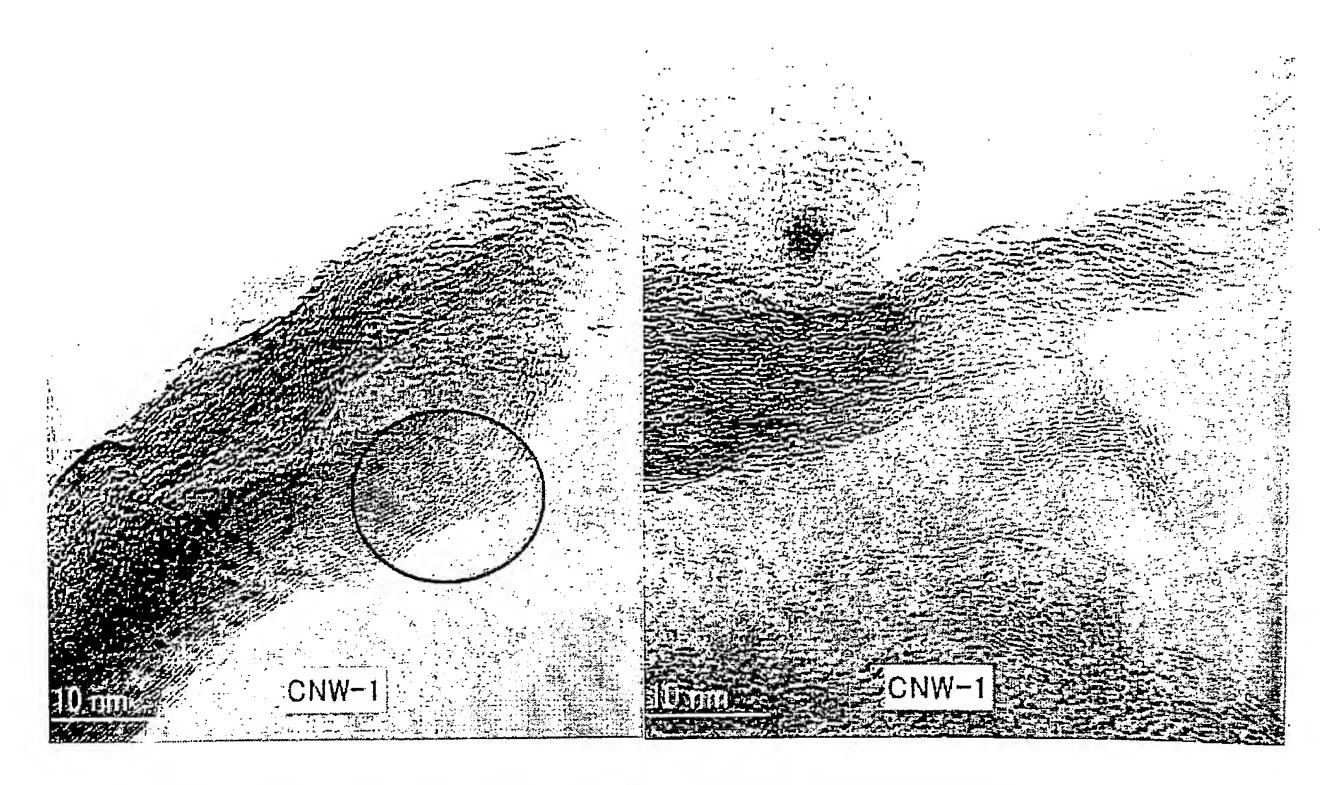
C₂F₆/H₂=20/80 CCP 100W, ICP 400W Si (100) SUBSTRATE SUBSTRATE TEMPERATURE OF 600°C GROWTH TIME OF EIGHT HOURS



ORIENTATION

GP 100W, ICP 400W
Si (100) SUBSTRATE
SUBSTRATE TEMPERATURE OF 600°C
GROWTH TIME OF EIGHT HOURS





MAGNIFICATION OF THREE HUNDRED THOUSAND

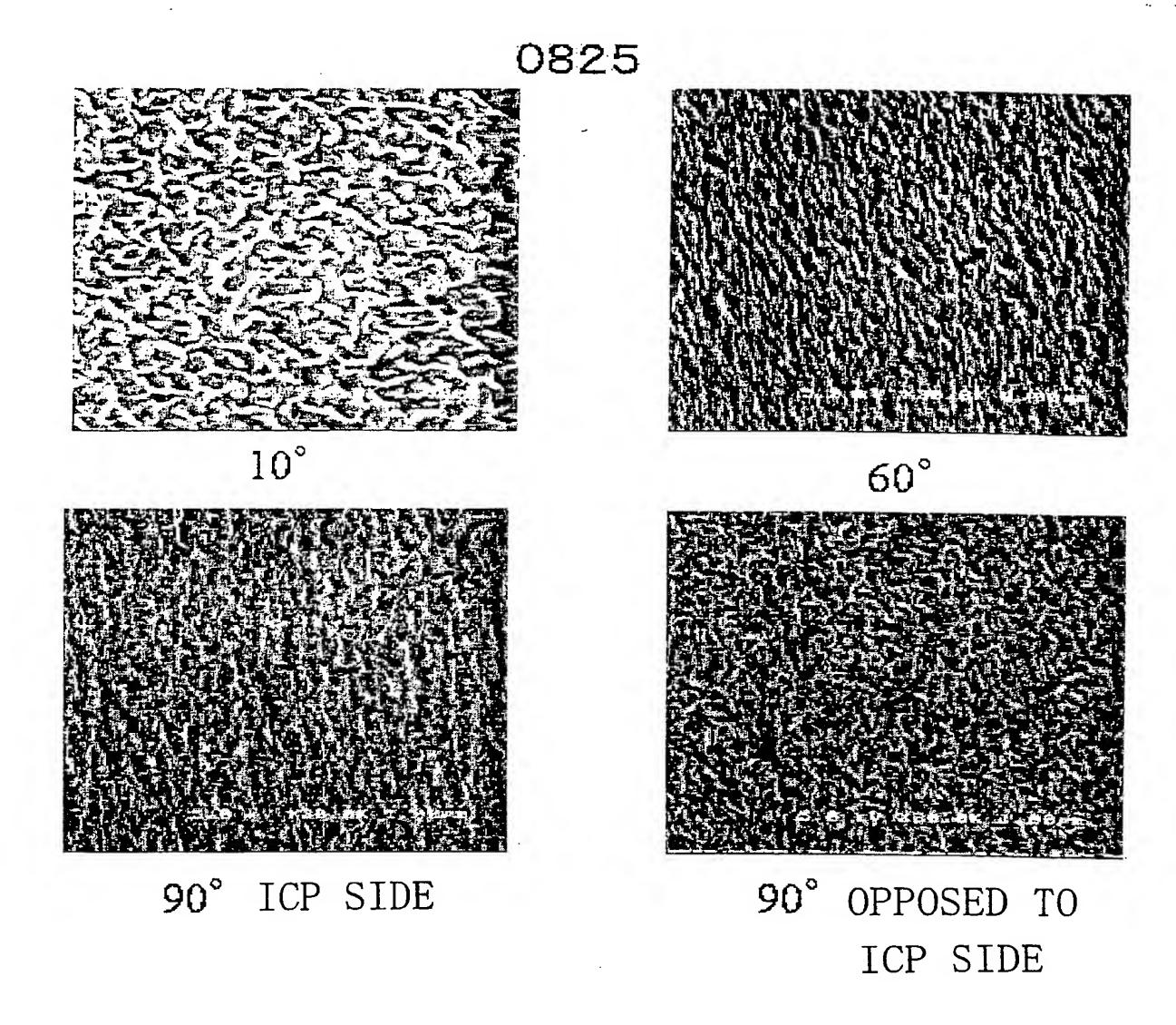
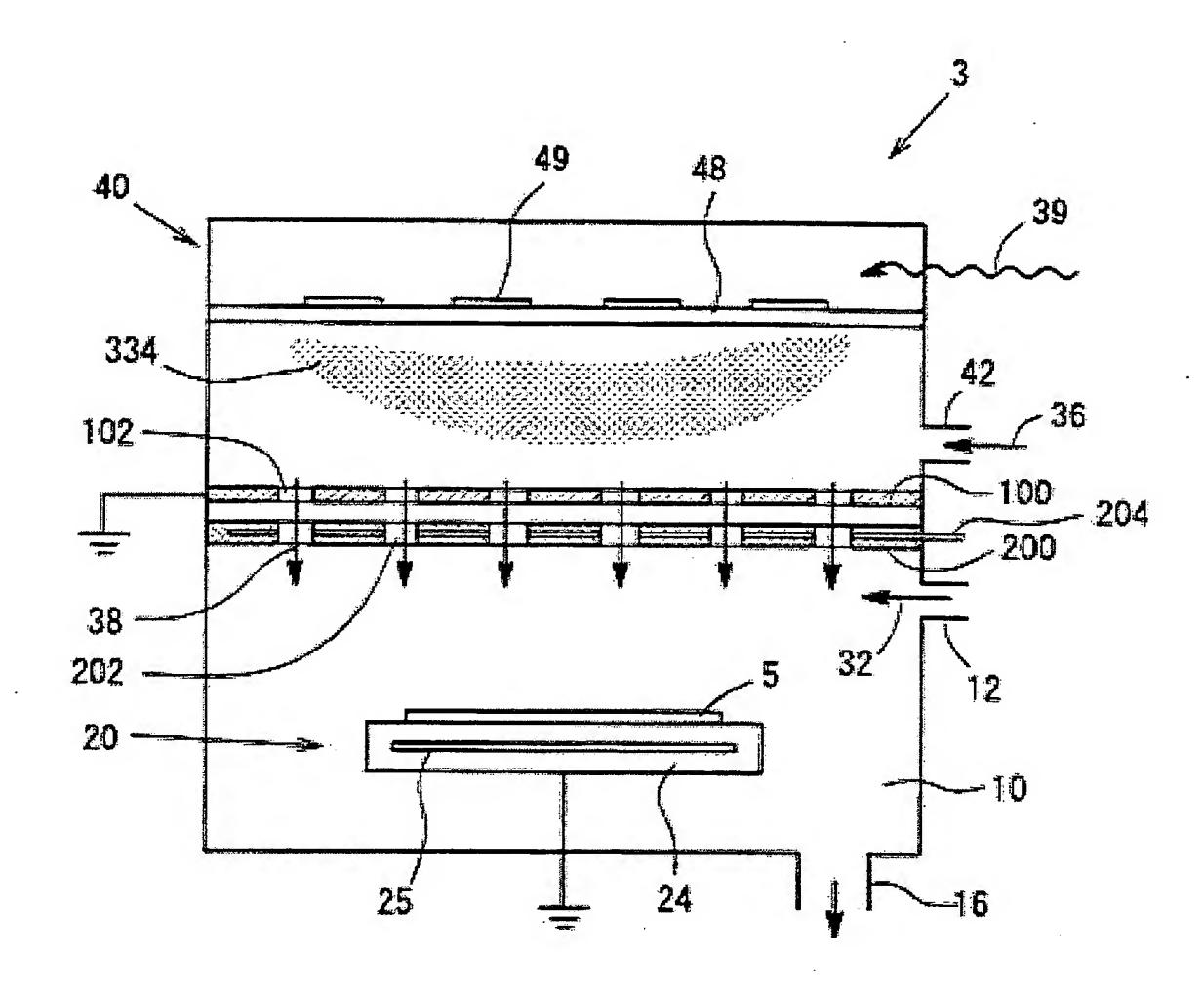
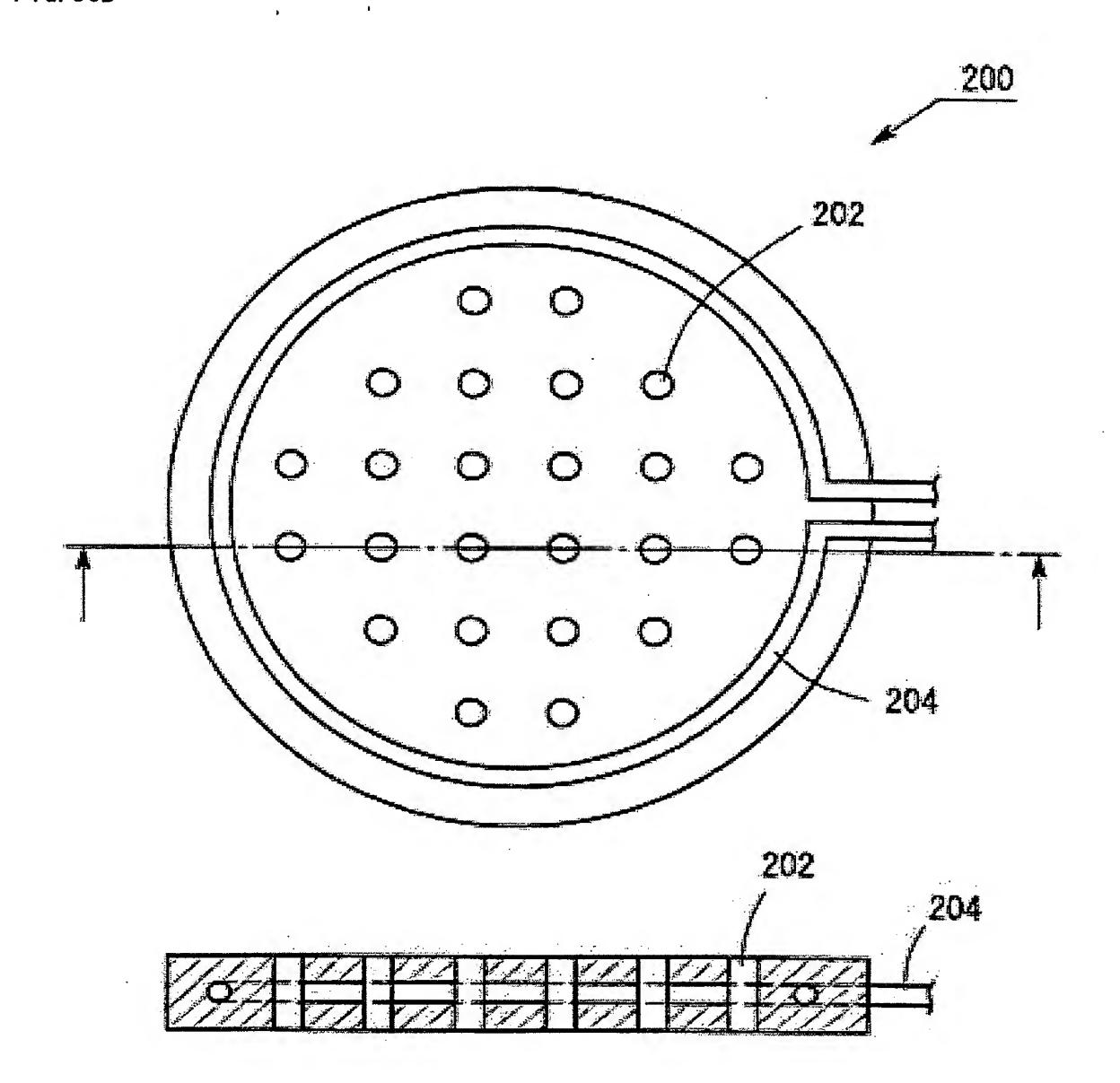
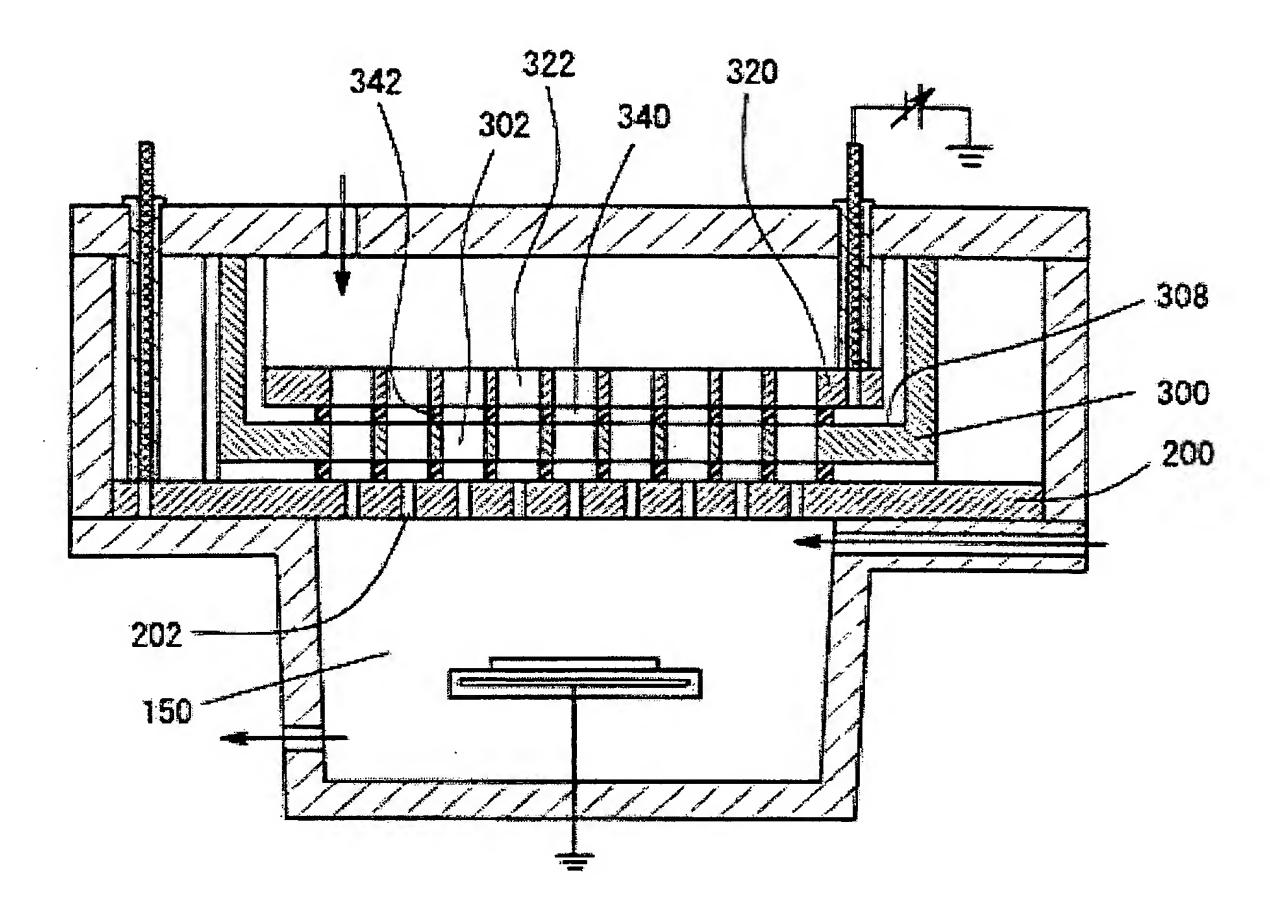


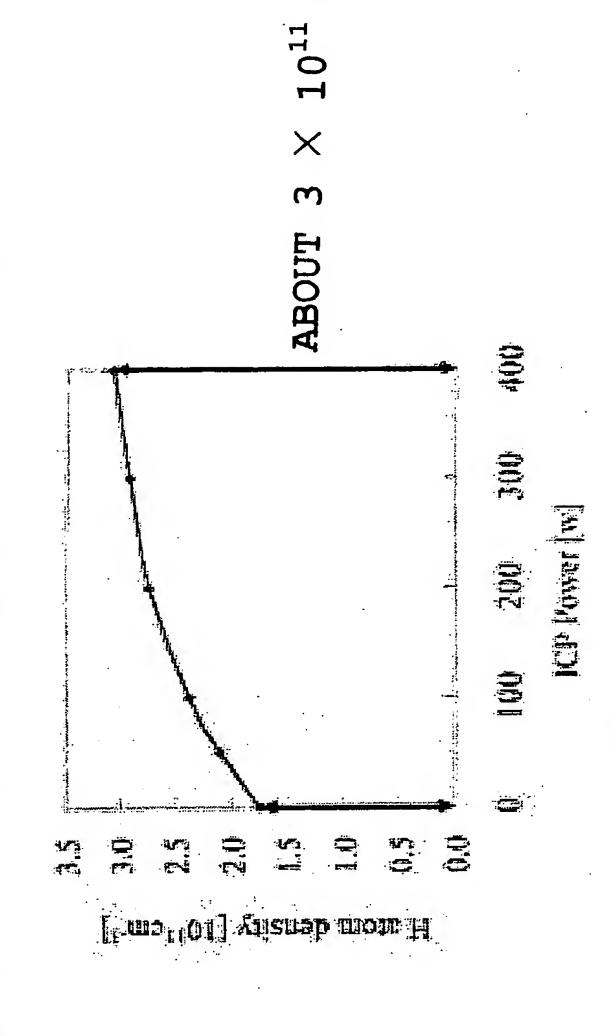
FIG. 56A







CHANGE IN HYDROGEN ATOM DRNSITY DUE TO VARIATION ON COUPLED PLASMA OUTPUT OF 100W) INDUCTIVELY COUPLED PLASMA (INDUCTIVELY **可** OUTPUT



BETWEEN ATOMIC DENSITIES

ABOUT TWO TIMES DIFFERENCE

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